

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/618,297	<b>Applicant(s)/Patent under Reexamination</b> WANG ET AL.
	<b>Examiner</b> Patrick J. Lee	<b>Art Unit</b> 2878

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference search		1/3/2006	PL